

**Search Notes****Application/Control No.**

10/531,924

**Applicant(s)/Patent under  
Reexamination**

FUKUI ET AL.

**Examiner**

Huyen Le

**Art Unit**

3751

**SEARCHED**

Class	Subclass	Date	Examiner
401	6 7	6/10/2008	HL
15	435		
16	430		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR